Errata

Document Title: Multi-Frequency C-V Measurements and Doping Profile Analysis of Semiconductors (AN 339-5)

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HP References in this Application Note

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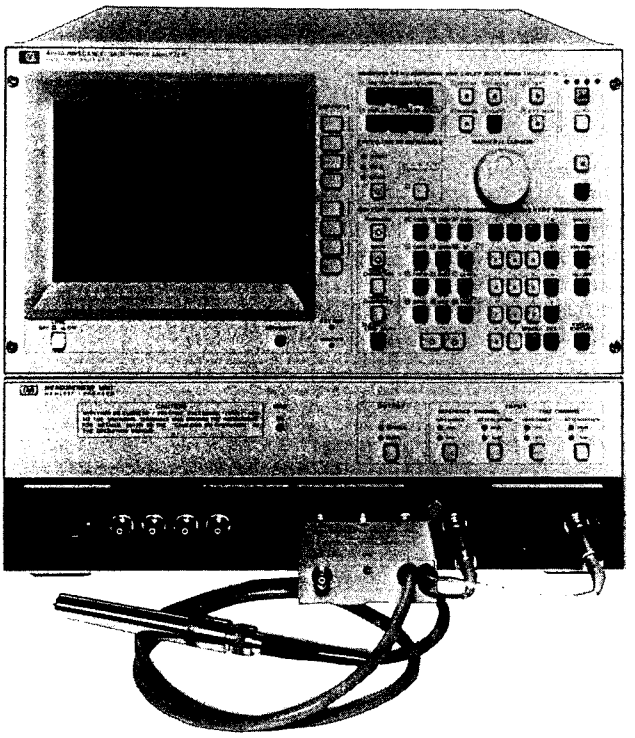
Application Note 339-5

Multi-frequency C-V Measurements and Doping Profile Analysis of Semiconductors

- HP 4194A Application Information -



HP 4194A Impedance/Gain-Phase Analyzer
with HP 41941A Impedance Probe Kit

Introduction

The HP 4194A Impedance/Gain-Phase Analyzer is the best choice for multi-frequency C-V measurements of semiconductors, thanks to its wide measurement frequency range (100kHz to 100MHz when used with the HP 41941A/B Impedance Probe Kit), precise measurement capability--even if the 1.5m/3m long probe is used, its optimized measurement performance and its ability to display directly plot measurement results. This application information describes how the HP 4194A contributes to new material and process development semiconductor labs.

Problems and Solutions Offered by the HP 4194A

Multi-frequency

As the operating frequency of devices has increased above 1MHz, the test frequency range for C-V measurements has increased accordingly.

Low frequency (such as 100kHz) measurements are required when measuring large diameter wafers. Because the thinness of large diameter wafers result in a higher series resistance at higher frequencies. (Refer to Figure 1), especially for high resolution oxide-layer capacitance (Cox) and depletion-layer capacitance (Cd) measurements.

—) The HP 4194A's measurement frequency, 100Hz to 40MHz (standard), or 10kHz to 100MHz when using the HP 41941A/B Impedance Probe Kit, covers both of these measurement requirements.

Extension Cable to Prober Station

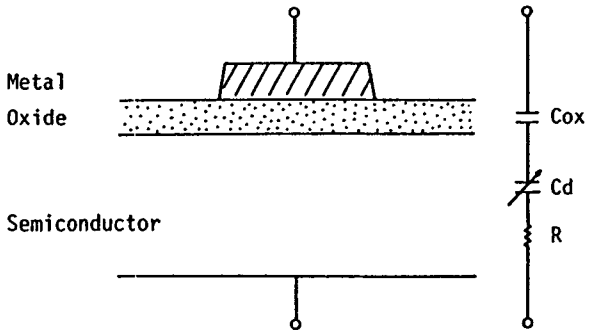
An extension cable from an LCR meter to a prober station (approximately 1 to 3m) causes measurement errors, and accurate measurements at frequencies above 1MHz may become impossible. By using the HP 41941A/B Impedance Probe Kit with the HP 4194A, you can make precise measurements up to 100MHz using a 1.5m or 3m long impedance probe, without the measurement errors caused by an extension cable.

C-V Curve Plotting and Calculation for Doping Profile

In the past, an external computer was needed to plot a C-V curve and to calculate a doping profile (N(w) vs. w*). Doping profiles from C-V data are most commonly used for the evaluation of semiconductor device structures and processing methods.

—) The HP 4194A's built-in color CRT can simultaneously display a C-V curve and doping profile. The Auto Sequence Program (ASP) function can be used to display these parameters quickly and automatically. Figure 3 shows a sample program. A quick hardcopy is also available (see Figures 5 and 6).

* N(w): Doping Profile
  w: Depth



$$Z = R + \frac{1}{j(2\pi f(Cox + Cd))}$$

Cox: Oxide-layer capacitance

Cd: Depletion-layer capacitance

R: Series Resistance

Figure 1 A Model of MOS Structure

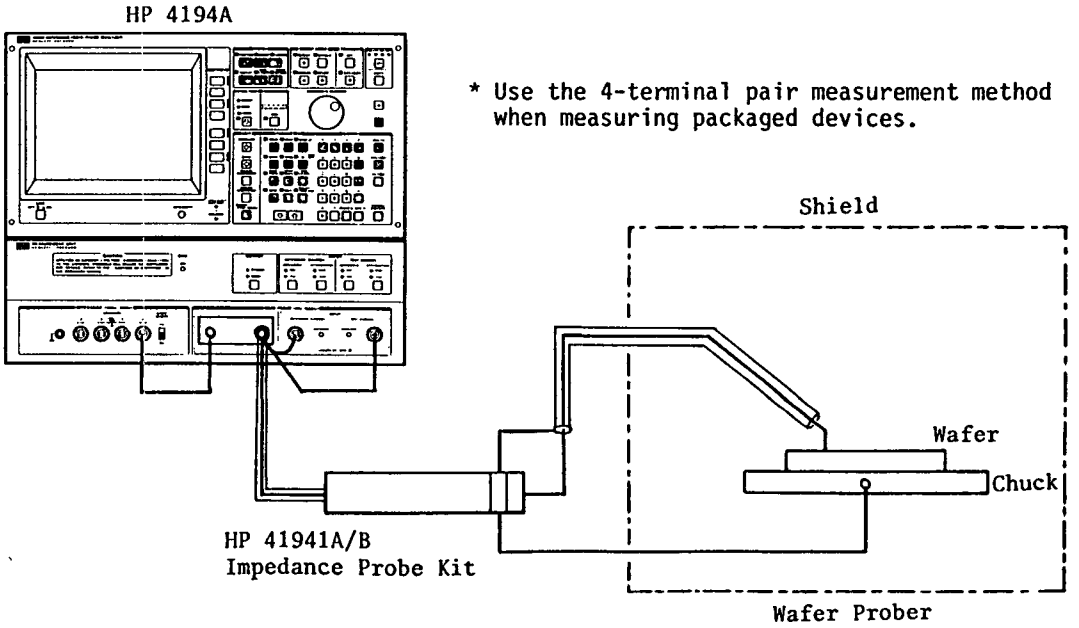


Figure 2 Measurement Setup
(HP 4194A + HP 41941A/B)

```
 10 RST
 20 CMT "**** MULTI FREQUENCY C-V CHARACTERISTIC ****"
 30 ! FNC1;IMP12        ! IMPEDANCE
 40   FNC3;IMP12        ! IMP. WITH Z PROBE
 50 UNIT0;SWM2;OPN1;SHT1
 60 BEEP
 70 Z=0
 80 DISP "COMPENSATION? / Y->INPUT <1>"
 90 PAUSE
100 IF Z=1 THEN GOSUB 730
110 R10= 8.854E-14      ! FREE SPACE PERMITIVITY
120 R12= 0.001          ! AREA OF THE GATE
130 R11=-1.602E-19      ! MAGNITUDE OF ELECTRONIC CHARGE
140 R13= 11.7           ! DIELECTRIC CONSTANT OF SI
150 SWP2;START=-5 V;STOP=5 V;STEP=.2 V
160 R51=NOP             ! NUMBER OF POINT
170 R50=R51-1           !
180 R52=20000           ! HOLD TIME  (MSEC)
190 R53=100             ! DELAY TIME (MSEC)
200 DISP "CONNECT TEST DEVICE"
210 PAUSE
220 ! *** MEAS. START ***
230 FOR R1=1  TO 3
240     IF R1=1 THEN FREQ=100 KHZ;GOTO 270 ! SET SPOT FREQUENCY
250     IF R1=2 THEN FREQ=  1 MHZ;GOTO 270
260                  FREQ= 10 MHZ
270     DTIME=R52;TRGM2
280     SWTRG
290     TRIG
300     DTIME=R53
310     TRGM1;MCF1;MKMXA
320     IF R1=1  THEN E=A;R5=MKRA;GOTO 350  ! 100 KHZ DATA TO E
330     IF R1=2  THEN F=A;R6=MKRA;GOTO 350  ! 1 MHZ DATA   TO F
340                    G=A;R7=MKRA          ! 10 MHZ DATA  TO G
350 NEXT R1
360 AMAX=1;BMAX=1;AMIN=0;BMIN=0;A=G/R7;B=F/R6;SPSTR;A=E/R5;SPA1;CPYM3
370 DISP "A=100 KHZ/B=1 MHZ/C=10 MHZ"
380 BEEP
390 PAUSE
400 CMT "          **** DOPING PROFILE ****"
410 R20=2/(R11*R10*R13*(R12**2))
420 R21=R12*R10*R13
430 FOR R1=1 TO R50
440     R2=R1+1
450     H(R1)=(1/(E(R2)*E(R2))-1/(E(R1)*E(R1)))/STEP
460     H(R1)=R20/H(R1)                     ! 100 KHZ N(W)
470     I(R1)=(1/(F(R2)*F(R2))-1/(F(R1)*F(R1)))/STEP
480     I(R1)=R20/I(R1)                     ! 1 MHZ   N(W)
490     J(R1)=(1/(G(R2)*G(R2))-1/(G(R1)*G(R1)))/STEP
500     J(R1)=R20/J(R1)                     ! 10 MHZ  N(W)
510 NEXT R1
520 H(R51)=H(R50);I(R51)=I(R50);J(R51)=J(R50);H=ABS(H);I=ABS(I);J=ABS(J)
530 RA=R21*(1/E-1/R5)                       ! 100 KHZ W
540 RB=R21*(1/F-1/R6)                       ! 1 MHZ   W
550 RC=R21*(1/G-1/R7)                       ! 10  MHZ  W
560 DSP2;BSC2;DPAB0
570  GOSUB 820
```

```
580 DPAB1
590 FOR R1=1 TO 3
600 IF R1=1 THEN A=RA;B=H ;GOTO 630
610 IF R1=2 THEN A=RB;B=I ;GOTO 630
620              A=RC;B=J
630 AMAX=R91;AMIN=R92;BMIN=R93;BMIN=R94
640 BEEP
650 IF R1=1 THEN CMT "          **** DOPING PROFILE AT 100KHZ ****" ;GOTO 680
660 IF R1=2 THEN CMT "          **** DOPING PROFILE AT 1MHZ   ****" ;GOTO 680
670              CMT "          **** DOPING PROFILE AT 10MHZ  ****"
680 DISP " ---> PRESS (CONT) "
690 PAUSE
700 NEXT R1
710 DISP "COMPLETED !"
720 END
730 ! **** COMPENSATION SUBROUTINE ****
740   BEEP
750   DISP "OPEN !"
760   PAUSE
770   ZOPEN
780   DISP "SHORT !"
790   PAUSE
800   ZSHRT
810 RETURN
820 ! **** AUTO SCALE SUBROUTINE ****
830 FOR R90=1 TO 3
840     IF R90=1 THEN A=E ;B=H ;GOTO 870
850     IF R90=2 THEN A=F ;B=I ;GOTO 870
860                   A=G ;B=J
870     AUTO
880     IF R90=1 THEN R91=AMAX ;R92=AMIN ;R93=BMAX ;R94=BMIN ;GOTO 910
890     IF R90=2 THEN R81=AMAX ;R82=AMIN ;R83=BMAX ;R84=BMIN ;GOTO 910
900                   R71=AMAX ;R72=AMIN ;R73=BMAX ;R74=BMIN
910 NEXT R90
920     IF R91<R81 THEN R91=R81
930     IF R91<R71 THEN R91=R71
940     IF R92>R82 THEN R92=R82
950     IF R92>R72 THEN R92=R72
960     IF R93<R83 THEN R93=R83
970     IF R93<R73 THEN R93=R73
980     IF R94>R84 THEN R94=R84
990     IF R94>R74 THEN R94=R74
1000 RETURN
```

Figure 3 ASP Program Listing

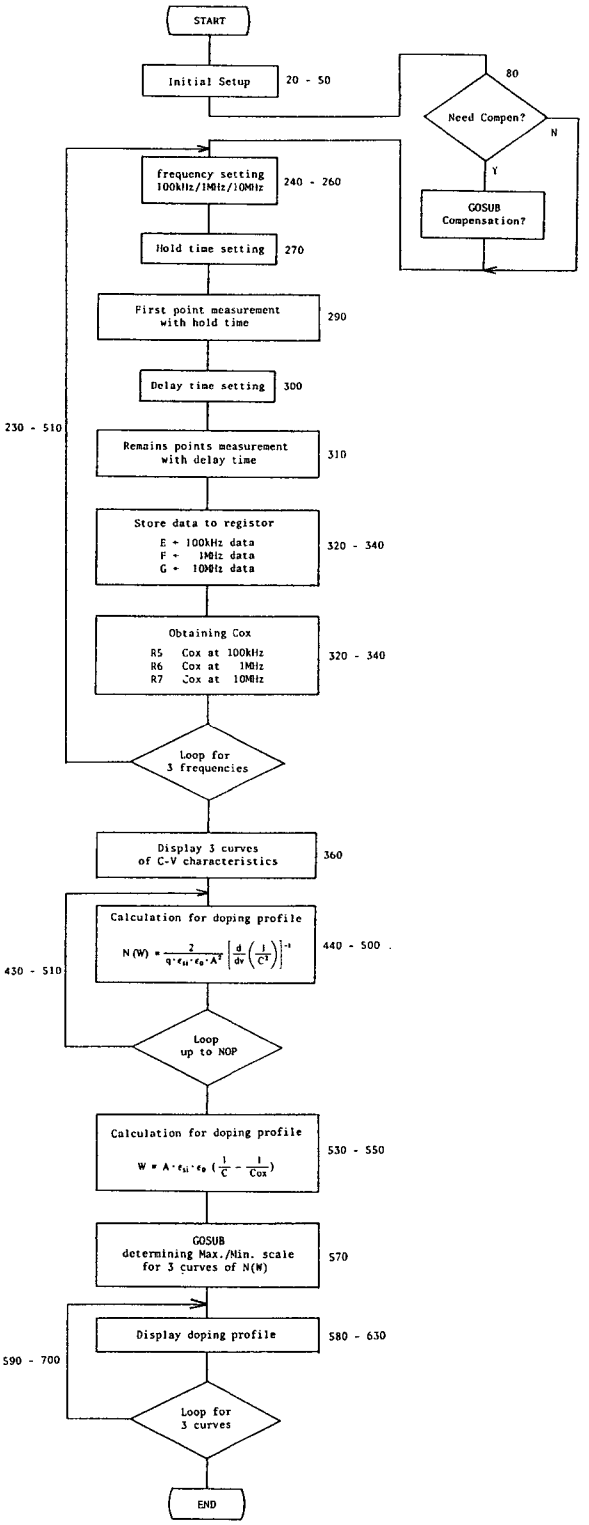


Figure 4 ASP Flow Chart

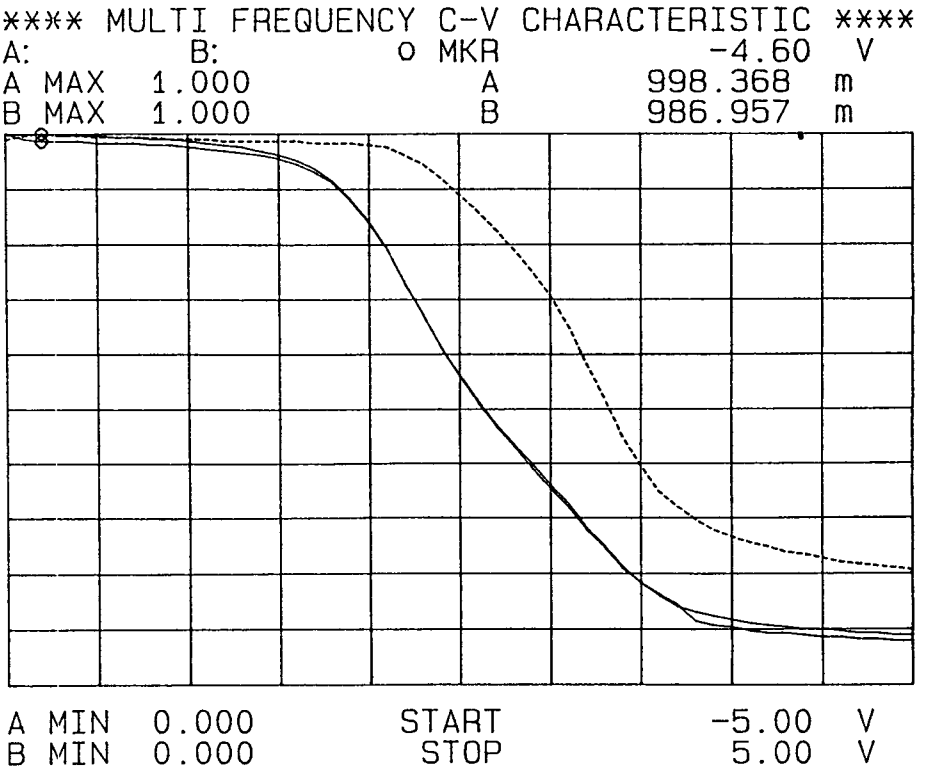


Figure 5 Example C-V Curve Display

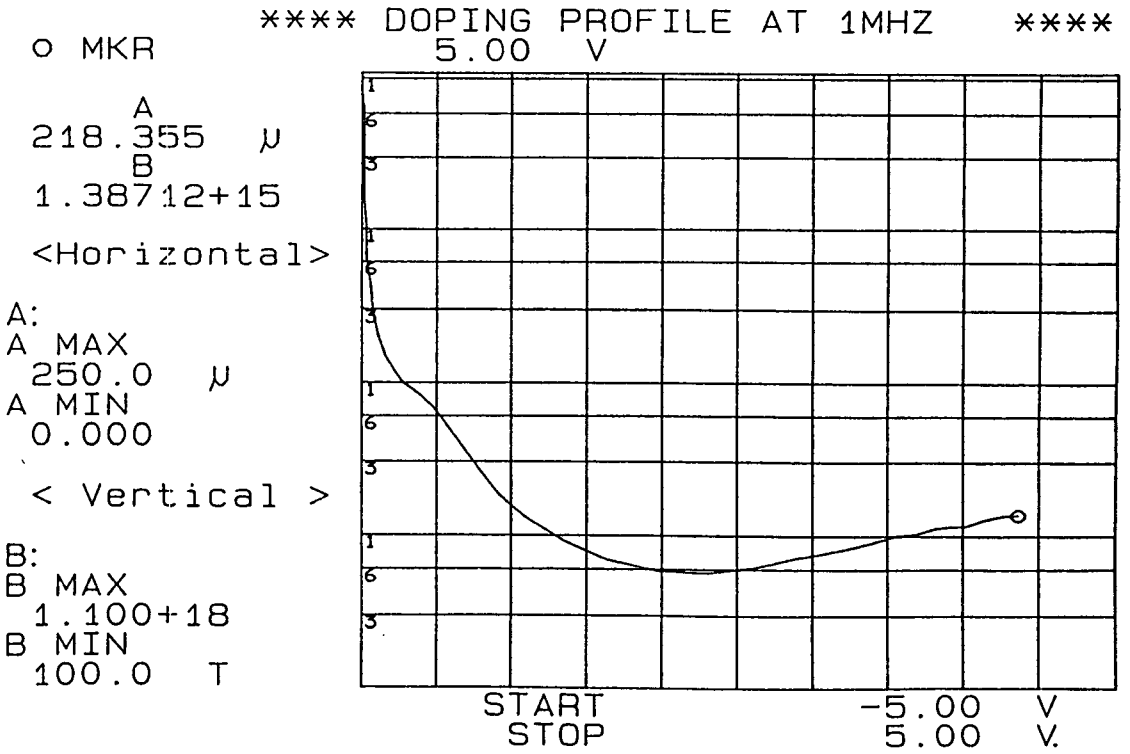


Figure 6 Example Doping Profile Display

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